COMING EVENTS

- (***): Contact Microscopy Today for further information.
- Nov 4/6 '92: ALEX '92: Analytical Laboratory Equipment Conference. San Francisco, CA. (***)
- ✓ Nov 8/13 '92: AVS Short Courses: Vacuum Technology Surface Science and Technology Thin Films and Coatings Materials: Processing/Characterization Chicago, IL. Margaret Banks: (212)661-9404.
- ✓ Nov 9/11 '92: Computer-Assisted Image Analysis & Measurement. Chicago, IL. Bruce Winston/Cindy Allen: (919)515-2261.
- Nov 16/20 '92: 31st Annual Eastern Analytical Symposium. Somerset, N.J. (302)738-6218.
- ✓ Nov 30-Dec 4 '92: Fall Meeting of the MRS. Boston, MA. (412)367-3003.
- ✓ Dec 2/4 '92: Modern Materials Analysis (MRS). Boston, MA. (412)367-3003.
- Dec 6/7 '92: Surface and Thin Film Analysis (MRS). Boston, MA. (412)367-3003.
- January 5/8 '93: John M. Cowley Symposium on Aspects of Electron Microscopy,

- Diffraction, Crystallography and Spectroscopy. Scottsdale, AZ. David J. Smith (602)965-4554; Sharon Willison (602)965-4544: FAX: (602)965-9004.
- January 11/15 '93: 1993 Winter School on High Resolution Electron Microscopy. Tempe, AZ. Sharon Willison: (602)965-4544; FAX: (602)965-9004.
- Feb 2/5 '93: Digital Microscopy School (Gatan, Inc.) Pleasanton, CA. Hans de Ruljter: (510)463-0200.
- Feb 8/11 '93: PEELS and Imaging Filter School (Gatan, Inc) Mike Kundman: (510)463-0200.
- March 8/12 '93: PITTCON '93. Atlanta, GA. (412)825-3220.
- March 8/10 '93: Microtomy for Material Science Application. (Univ of Arizona & ARM Inc.). Tucson, AZ. Bob Chiovetti: (602)889-7900.
- March 22/26, 29/April 2, '92: Practical Aspects of Scanning Electron Microscopy (Univ. of MD Short Course). College Park, MD. Tim Maugel: (301)405-6898.
- April 21/23 '93: SCANNING '93 Conference. Orlando, FL. Mary K. Sullivan: (201)818-1010

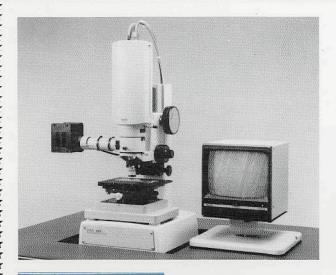
- May 5/7 '93: 1st International Symposium on Computerized Data Standards: Databases, Data Interchange, and Information Systems. Atlanta, GA. Dorothy Savini: (215)299-5413.
- June 6/10 '93: Molecular Microspectroscopy (9th Annual short course & workshop). Miami Univ., Oxford, OH. (513)529-2873.

THE LEHIGH SEM/AEM/SPM COURSES '93 June 14/18 '93: Basic Course: Scanning Electron Microscopy & X-ray Analysis.

- June 21/25 '93: Advanced Courses:
 - 1) Microcharacterization of Electronic Materials, Devices and Packages.
 - Advanced Scanning Imaging.
 - 3) Quantitative X-ray Microanalysis of Bulk Specimens and Particles.
 - 4) AFM, STM and Other Scanned Probe Microscopies.
- June 21/24 '93: Analytical Electron Microscopy.
- June 24/25 '93: Thin Specimen Preparation.

For detailed information, contact Professor Joseph Goldstein: Tel.: (215)758-5133 ********

July 11/16 '93: Microbeam Analysis Annual Meeting. Los Angeles, CA. Jack Worrall, MAS '93, PO Box 1014, Monrovia, CA 91017-1014.





WYKO RST SURFACE PROFILER

The new WYKO RST Rough Surface Tester rapidly measures roughness and step heights to 100 um on surfaces such as textured aluminum and steel, etched silicon, plastics, magnetic tape and diskettes, ceramics, and even paper. The RST optical profiler features DSP electronics that measure areas much faster than stylus systems and without the problems associated with X/Y surface scanning. Each data point is processed independently, so surfaces with discontinuities or steeply sloped subareas can be measured without those regions affecting the surrounding data. Results are displayed as three-dimensional color graphics along with industry-standard surface statistics. The RST DOS-based software features database and easy networking for process control applications. WYKO's microsurface measurement systems are the most widely used optical profilers in the world.